## Notice of References Cited

I	Application/Control No. 10/764,483	Applicant(s)/Patent Under Reexamination LEE, GUN-IL		
	Examiner	Art Unit		
	Allen H. Nauven	2625	Page 1 of 1	

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,385,728	05-2002	DeBry, Roger K.	726/9
*	В	US-2003/0002072	01-2003	Berkema et al.	358/1.15
*	С	US-5,727,890	03-1998	Stodder et al.	400/624
*	D	US-2002/0016833	02-2002	Yajima et al.	709/220
*	Е	US-2002/0024684	02-2002	Tanimoto, Yoshifumi	358/400
*	F	US-7,268,899	09-2007	Crumly, James D.	358/1.14
	G	US-			
	Н	US-			
		US-			
	J	US-			
	к	US-			
	L	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		1			
	R					
	s					
	т					

## NON-PATENT DOCUMENTS

*	NON-FATENT DOCUMENTS			
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	٧			
	w			
	x			

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.